

# **MOSFET** - N-Channel, QFET

## 250 V, 14 A, 110 mΩ

## FQPF27N25

#### Description

This N-Channel enhancement mode power MOSFET is produced using onsemi's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

#### **Features**

- 14 A, 250 V,  $R_{DS(on)} = 110 \text{ m}\Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 7 \text{ A}$
- Low Gate Charge (Typ. 50 nC)
- Low C<sub>rss</sub> (Typ. 45 pF)
- 100% Avalanche Tested
- This is a Pb-Free Device

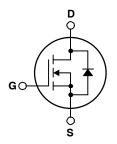
## ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V <sub>DSS</sub>	Drain to Source Voltage	250	V
I <sub>D</sub>	$ \begin{array}{ll} \text{Drain Current} & -\text{Continuous } (T_C = 25^{\circ}\text{C}) \\ -\text{Continuous } (T_C = 100^{\circ}\text{C}) \end{array} $	14 8.9	A A
I <sub>DM</sub>	Drain Current -Pulsed (Note 1)	56	Α
V <sub>GSS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)	600	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)	14	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)	5.5	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	5.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)  -Derate Above 25°C	55 0.44	W W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	–55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 5 seconds	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. L = 4.9 mH,  $I_{AS}$  = 14 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25  $^{\circ}$ C. 3.  $I_{SD} \le 27$  A, di/dt  $\le 300$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , Starting  $T_{J}$  = 25  $^{\circ}$ C.

V <sub>DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX	
250 V	110 m $\Omega$ @ 10 V	14 A	



**N-CHANNEL MOSFET** 



TO-220 Fullpack, 3-Lead / TO-220F-3SG CASE 221AT

#### **MARKING DIAGRAM**



FQPF27N25

= Specific Device Code

= Assembly Location

YWW

= Date Code (Year & Week)

ZZ

= Assembly Lot

#### **ORDERING INFORMATION**

Device	Package	Shipping
FQPF27N25	TO-220F (Pb-Free)	1000 / Tube

## THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.27	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W

## **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
FF CHARA	ACTERISTICS	•	•			
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	250	_	-	V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C	-	0.29	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 250 V, V <sub>GS</sub> = 0 V	-	_	1	μΑ
		V <sub>DS</sub> = 200 V, T <sub>C</sub> = 125°C	-	_	10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V	-	_	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$	-	_	-100	nA
N CHARA	CTERISTICS	•				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3.0	_	5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7.0 A	-	0.083	0.11	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 7.0 A	-	15	-	S
YNAMIC C	HARACTERISTICS	•				
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz	-	1900	2450	pF
C <sub>oss</sub>	Output Capacitance	7	-	360	470	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	7	-	45	60	pF
WITCHING	CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 125 V, I <sub>D</sub> = 27 A,	-	32	75	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$ (Note 4)	-	270	550	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1` '	-	80	170	ns
t <sub>f</sub>	Turn-Off Fall Time	7	-	120	250	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 200 V, I <sub>D</sub> = 27 A,	-	50	65	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V , (Note 4)	-	12.5	-	nC
$Q_{gd}$	Gate-Drain Charge	1` '	-	26	-	nC
RAIN-SOU	RCE DIODE CHARACTERISTICS AND M	MAXIMUM RATINGS				_
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current		-	_	14	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		-	_	56	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 14A	-	-	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 27 A,	-	220	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	_	1.8	-	μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially Independent of Operating Temperature.

#### **TYPICAL CHARACTERISTICS**

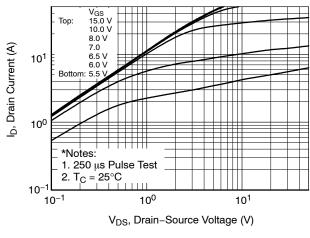


Figure 1. On-Region Characteristics

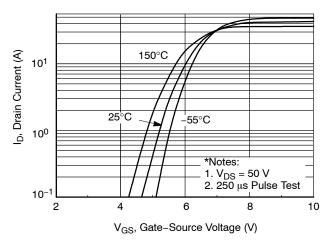


Figure 2. Transfer Characteristics

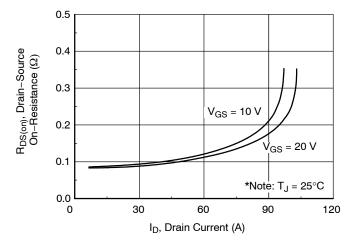


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

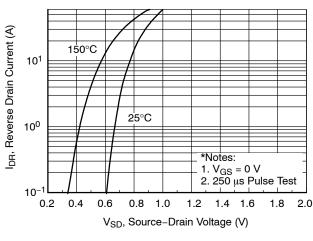


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

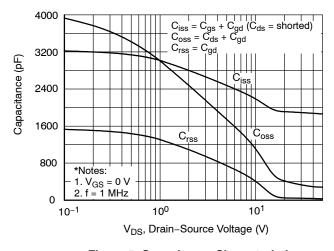


Figure 5. Capacitance Characteristics

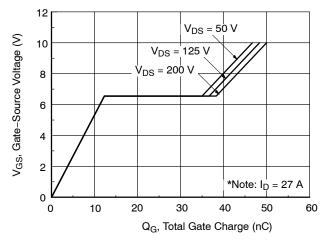


Figure 6. Gate Charge Characteristics

## TYPICAL CHARACTERISTICS (continued)

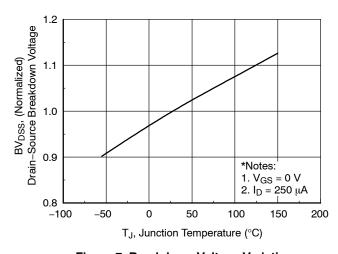


Figure 7. Breakdown Voltage Variation vs. Temperature

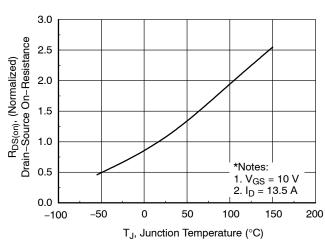


Figure 8. On-Resistance Variation vs. Temperature

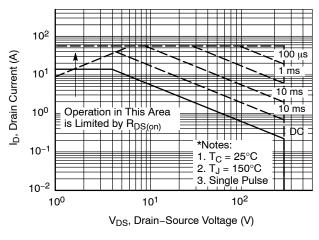


Figure 9. Maximum Safe Operating Area

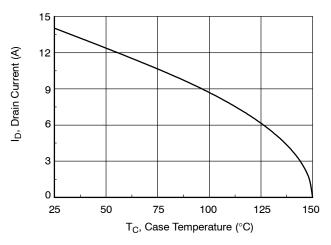


Figure 10. Maximum Drain Current vs. Case Temperature

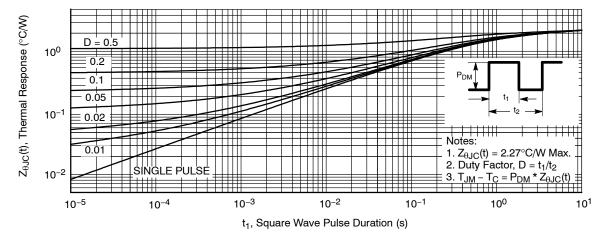


Figure 11. Transient Thermal Response Curve

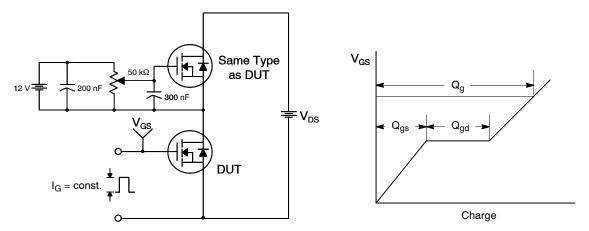


Figure 12. Gate Charge Test Circuit & Waveform

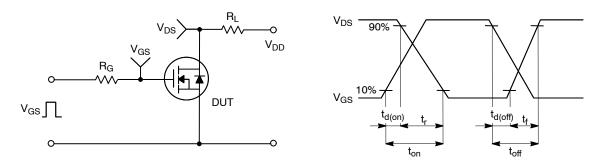


Figure 13. Resistive Switching Test Circuit & Waveforms

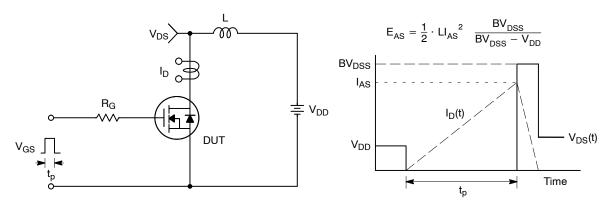


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

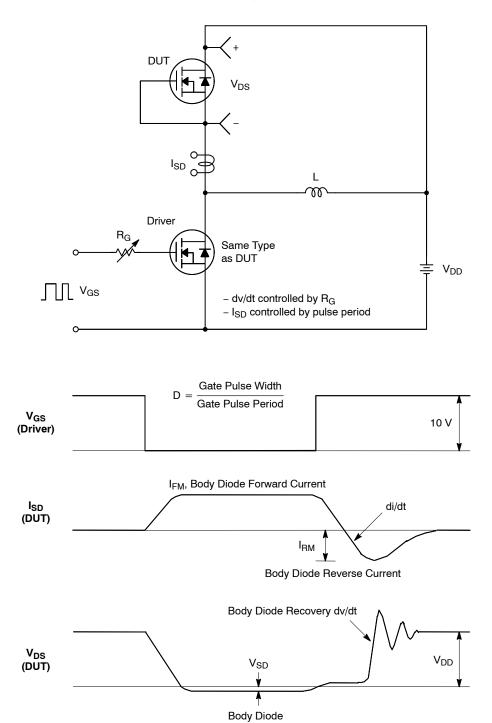
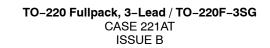
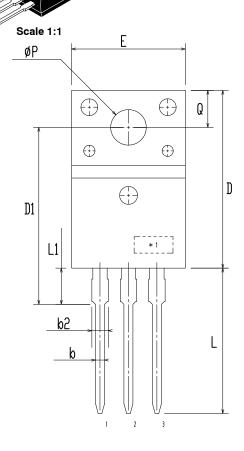


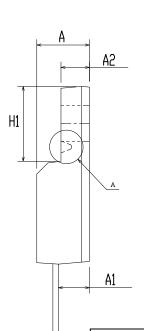
Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

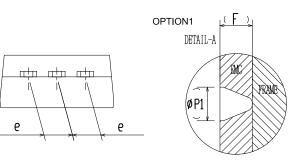
Forward Voltage Drop



**DATE 19 JAN 2021** 







DIM	MIL	LIMITERS	
DIM	MIN	NDM	MAX
Α	4.50	4.70	4.90
A1	2.56	2.76	2.96
A2	2.34	2.54	2.74
b	0.70	0.80	0.90
b2	*	2	1.47
C	0.45	0.50	0.60
D	15.67	15.87	16.07
D1	15.60	15.80	16.00
E	9.96	10.16	10.36
е	2.34	2.54	2.74
F	2	0.84	2
H1	6.48	6.68	6.88
L	12.78	12.98	13.18
L1	3.03	3.23	3.43
ØΡ	2.98	3.18	3,38
Ø P1	~	1.00	~
Q	3.20	3.30	3.40

#### NOTES:

- A. DIMENSION AND TOLERANCE AS ASME Y14.5-2009
- B. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUCSIONS.

C

C. OPTION 1 - WITH SUPPORT PIN HOLE OPTION 2 - NO SUPPORT PIN HOLE

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